Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/807,724	MCDOWALL ET AL.	
Examiner	Art Unit	
Tran N. Nguyen	2834	

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED						
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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